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M Sachdev, P Janssen, V Zieren - Proceedings of the 1998 IEEE International Test Conference, 1998 - doi.ieeeecs.org

... equally important to find out which transient current segments are ... device provides the key for fault detection ... only the peak and the quiescent current level of ...

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[Transient power supply current testing of digital CMOS circuits](#)

RZ Makki, ST Su, T Nagle - Test Conference, 1995. Proceedings., International, 1995 - [ieeexplore.ieee.org](#)

... assume that the normal dynamic (transient) current ... is distinguishably higher than the quiescent current ZDD ... the absence of the IDD pulse indicates a fault. ...

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[Quiescent power supply current measurement for CMOS IC defect detection](#)

CF Hawkins, JM Soden, RR Fritzsche, LK Horning - Industrial Electronics, IEEE Transactions on, 1989 - [ieeexplore.ieee.org](#)

... that exists in a CMOS circuit when all logic states have settled and are in a steady state or quiescent mode. Transient power supply current is the ...

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... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the IDD current and compare ...

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[Built-in current testing of integrated circuits](#)

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - [freepatentsonline.com](#)

... 50, 100 and 150 nanoseconds, a large transient current occurs then ... The quiescent value may vary for different IC circuits ... 6 shows current flow with a gate oxide ...

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[CURRENT VS. LOGIC TESTING OF GATE OXIDE SHORT, FLOATING GATE AND BRIDGING FAILURES IN CMOS](#)

R Rodriguez-Montanes, JA Segura, VH Champac, J ... - Test Conference, 1991, Proceedings., International, 1991 - [ieeexplore.ieee.org](#)

... shown that some failure mechanisms exhibit a transient behaviour, in transient current is; expressed in PA (in a fault-free circuit this quiescent current is in ...

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[Built-in current testing-feasibility study](#) - [► sigda.org PDF](#)

W Maly, P Nigh - Computer-Aided Design, 1988. ICCAD-88. Digest of Technical ..., 1988 - [ieeexplore.ieee.org](#)
... the boundary between normal and abnormal quiescent currents ... the voltage drop during
peak transient currents ... Compare the voltage across the current Sensor of the ...
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Transient power supply current monitoring—A new test method for CMOS VLSI circuits
ST Su, RZ Makki, T Nagle - Journal of Electronic Testing, 1995 - Springer
... Design for current-testability, drain/source opens, floating gates, shorts, transient
power supply ... IDD Q (quiescent power supply current) testing has ...
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Quiescent current analysis and experimentation of defective CMOS circuits
JA Segura, VH Champac, R Rodríguez-Montañés, J ... - Journal of Electronic Testing, 1992 - Springer
... in the field using Inductive Fault Analysis [1], [2 ... Limited experimental data on
quiescent current meas- ures are ... of the influence of defect characteristics on ...
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Detection and location of faults and defects using digital signal processing
C Thibault - VLSI Test Symposium, 1995 - [doi.ieeeecs.org](#)
... be useful for tech- nologies with significant quiescent current, since their ... ples
(once per clock period) current when ICs ... when the chips are in transient state ...
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Increased CMOS IC stuck-at fault coverage with reduced I DDQ test sets
RR Fritzemeier, JM Soden, RK Treece, CF Hawkins - Test Conference, 1990. Proceedings., International, 1990 - [ieeexplore.ieee.org](#)
... produce elevated quiescent current in one or more logic states. ... logic 0 and 1 (non-
transient logic states ... The difference in untestable fault counts between the ...
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Defect Detection Using Power Supply Transient Signal Analysis - [►umbc.edu \(pdf\)](#)
A Germida, Z Yan, JF Plusquellic, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - [doi.ieeecomputersociety.org](#)
... on the analysis of a circuit's parametric properties, for example, propagation delay,
magnitude of quiescent supply current or transient response [5 ...
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Built-in current sensor for I DDQ test in CMOS
CW Hsue, CJ Lin - Test Conference, 1993. Proceedings., International, 1993 - [ieeexplore.ieee.org](#)
... requirement of large current sink for state-transition transient current. ... RR Fritzemeier
and LK Homing, "Quiescent power supply current measurement for ...
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Defect-oriented test methodology for complex mixed-signal circuits
FCM Kuijstermans, M Sachdev, AP Thijssen - European Design and Test Conference, 1995. ED&TC 1995, ..., 1995 - [ieeexplore.ieee.org](#)
... can be detected by simple DC, Transient and AC ... due to a leakage current, the quiescent
current is strongly ... Defect simulation and fault collapsing The defect sim ...
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Electrical Model of the Floating Gate Defect in CMOS IC's: Implications on I~ D~ D~ Q Testing
VH Champac, A Rubio, J Figueras - IEEE TRANSACTIONS ON COMPUTER AIDED DESIGN OF INTEGRATED ..., 1994 - [ieeexplore.ieee.org](#)
... chip with transistors possessing floating gate defects. ... characteristics of both the
fault-free transistor ... which produces the same equivalent quiescent current. ...

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Transient current testing based on current (charge) integration

I de Paul, R Picos, JL Rossello, M Roca, E Isern, ... - IDDQ Testing, 1998. Proceedings. 1998 IEEE International ..., 1998 - [ieeexplore.ieee.org](#)

... consumption not only during the quiescent periods, but ... Since this technique monitors the transient current, the test ... were chosen to induce a current path in ...

[Cited by 10](#) - [Related articles](#) - [Web Search](#) - [All 3 versions](#)

Experimental analysis of transient current testing based on charge observation

J Segura, I De Paul, M Roca, E Isern, CF Hawkins - Electronics Letters, 1999 - [ieeexplore.ieee.org](#)

... current and changed only the transient part of the ... charge value was beyond the fault free charge ... Open circuits causing quiescent current elevation in latch ...

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IDDQ testing of CMOS opens: an experimental study

AD Singh, H Rasheed, WW Weber - Test Conference, 1995. Proceedings., International, 1995 - [ieeexplore.ieee.org](#)

... a stable state following a switching transient. Any quiescent current drawn from the power rails, beyond the background junction leakage current, indicates a ...

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A 2-ns detecting time, 2- μ m CMOS built-in current sensing circuit

TL Shen, JC Daly, JC Lo - Solid-State Circuits, IEEE Journal of, 1993 - [ieeexplore.ieee.org](#)

... minimum of 2-ns duration of quiescent power supply current (without excessive transient current) is needed for an accurate current testing result ...

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Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. ..., 1988 - [ieeexplore.ieee.org](#)

... In such circuits, peak values of transient currents are ... faulty and "fault-free" quiescent currents. ... simulations, one can estimate current differences smaller ...

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... Quiescent current testing (I DDQ) is an important ... To prove the fault detection capability of this method ... Because the transient current waveforms may differ in ...

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R Rodriguez-Montanes, JA Segura, VH Champac, J ... - Test Conference, 1991, Proceedings., International, 1991 - ieeexplore.ieee.org

... shown that some failure mechanisms exhibit a transient behaviour, in transient current is; expressed in PA (in a fault-free circuit this quiescent current is in ...

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[Defect Detection Using Power Supply Transient Signal Analysis - umbc.edu \(PDF\)](#)

A Germida, Z Yan, JF Plusquellic, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - doi.ieeecomputersociety.org

... measurement of an IC's supply current when all nodes have stabilized to a quiescent value. ... Defect Detection using Power Supply Transient Signal Analysis ...

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JA Segura, VH Champac, R Rodriguez-Montañés, J ... - Journal of Electronic Testing, 1992 - Springer
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defects investigated ... Limited experimental data on quiescent current meas- ures ...
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ST Su, RZ Makki, T Nagle - Journal of Electronic Testing, 1995 - Springer
... denotes the peak value of the quiescent supply current ... directly com- puted from the
transient portion of ... GOOD CKT FAULT CKT Current Response Current Response ...
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Detection and location of faults and defects using digital signal processing

C Thibeault - VLSI Test Symposium, 1995 - doi.ieeeecs.org
... be useful for tech- nologies with significant quiescent current, since their ... ples
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W Maly, P Nigh - Computer-Aided Design, 1988. ICCAD-88. Digest of Technical ..., 1988 - ieeexplore.ieee.org
... defines the boundary between normal and abnormal quiescent currents ... the voltage drop
during peak transient currents ... in which full adders and current sensors were ...
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IDDQ testing: A review

JM Soden, CF Hawkins, RK Gulati, W Mao - Journal of Electronic Testing, 1992 - Springer
... Abstract. Quiescent power supply current (IDDQ) testing of CMOS ... quality improvement
through increased defect and fault detection is described. ...
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CW Hsue, CJ Lin - Test Conference, 1993. Proceedings., International, 1993 - ieeexplore.ieee.org
... requirement of large current sink for state-transition transient current. ... RR Fritzemeier
and LK Homing, "Quiescent power supply current measurement for ...
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A 2-ns detecting time, 2- μ m CMOS built-in current sensing circuit

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current) is needed ... and P. Nigh, "Built-in current testing—Feasibility ...
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... a stable state following a switch- ing transient. Any quiescent current drawn from
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... In such circuits, peak values of transient currents are ... faulty and "fault-free"
quiescent currents. ... simulations, one can estimate current differences smaller ...
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Enhancement of resolution in supply current based testing for large ICs

YK Malaiya, AP Jayasumana, Q Tong, SM Menon - Proc. IEEE VLSI Test Symp, 1991 - doi.ieeecomputersociety.org

... such as NMOS and TTL, the quiescent current can be ... between states, and the noise in transient current to provide ... the testing of an IC by current measurements. ...

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Electrical Model of the Floating Gate Defect in CMOS IC's: Implications on I~ D~ D~ Q Testing

VH Champac, A Rubio, J Figueras - IEEE TRANSACTIONS ON COMPUTER AIDED DESIGN OF INTEGRATED ..., 1994 - ieeexplore.ieee.org

... chip with transistors possessing floating gate defects. ... characteristics of both the fault-free transistor ... which produces the same equivalent quiescent current. ...

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Increased CMOS IC stuck-at fault coverage with reduced I DDQ test sets

RR Fritzemeier, JM Soden, RK Treece, CF Hawkins - Test Conference, 1990. Proceedings., International, 1990 - ieeexplore.ieee.org

... produce elevated quiescent current in one or more logic states. ... logic 0 and 1 (non-transient logic states ... The difference in untestable fault counts between the ...

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Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - freepatentsonline.com

... including radiation induced latch-up or other transient faults. ... may result in still higher quiescent current flows which ... pads are use while current sensors are ...

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Experimental analysis of transient current testing based on chargeobservation

J Segura, I De Paul, M Roca, E Isern, CF Hawkins - Electronics Letters, 1999 - ieeexplore.ieee.org

... current and changed only the transient part of ... Open circuits caus- ing quiescent current elevation in latch ... with this technique; it drew less current than the ...

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... quite useful for detecting stuck-at faults themselves using a ... The peak of the transient current is approximately 60 ... in about 100 ns to a low quiescent current. ...

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... wait till the current has reached the quiescent level for ... to determine the total charge in a transient peak instead ... 18] integrated the I_{DD} current and compare ...

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... when the chips are in transient state ... technologies with significant supply quiescent current, since DC ... circuits based on supply current," in International ...

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[IDDQ testing: A review](#)

JM Soden, CF Hawkins, RK Gulati, W Mao - Journal of Electronic Testing, 1992 - Springer

... It may seem costly to reject ICs that have increased quiescent power supply current but are still performing their logic functions ... 4. Fault Detection ...

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[Test challenges for deep sub-micron technologies](#) - [►acm.org](#) (PDF)

KT Cheng, S Dey, M Rodgers, K Roy - Design Automation Conference, 2000. Proceedings 2000. 37th, 2000 - [ieeexplore.ieee.org](#)

... reduction techniques for the application of current testing ... of circuit and more complex fault types (eg ... DFT and test solutions and CAD environment ahead of time. ...

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[DELAY TESTING OF DIGITAL CIRCUITS BY OUTPUT WAVEFORM ANALYSIS](#)

P Franco, EJ McCluskey - Test Conference, 1991. Proceedings., International, 1991 - [ieeexplore.ieee.org](#)

... and fault-free waveforms before the sampling time, and compared ... required in the past, catastrophic fault models have ... These defects are modeled by delay faults. ...

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A Germida, Z Yan, JF Plusquellic, F Muradali - INTERNATIONAL TEST CONFERENCE, 1999 - [doi.ieeecomputersociety.org](#)

... nodes have stabilized to a quiescent value. ... Defect Detection using Power Supply Transient Signal Analysis ... Several dynamic supply current I_{DD}-based approaches ...

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Built-in current testing of integrated circuits

WP Maly, PJ Nigh - US Patent 5,025,344, 1991 - [freepatentsonline.com](#)
... including radiation induced latch-up or other transient faults. ... may result in still higher quiescent current flows which ... pads are use while current sensors are ...

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Enhancement of resolution in supply current based testing for large ICs

YK Malaiya, AP Jayasumana, Q Tong, SM Menon - Proc. IEEE VLSI Test Symp, 1991 - [doi.ieeecomputersociety.org](#)

... The width of transient current pulse, loading of VDD pin due to output buffers and ...
Let us assume that the additional quiescent supply current, if, is ...

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Transient current testing based on current (charge) integration

I de Paul, R Picos, JL Rossello, M Roca, E Isern, ... - IDDQ Testing, 1998. Proceedings. 1998 IEEE International ..., 1998 - [ieeexplore.ieee.org](#)

... con- sumption not only during the quiescent periods, but ... be achieved by measuring the transient current at the ... activity dif- ference between the fault free and ...

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Current sensing for built-in testing of CMOS circuits

DBI Feltham, PJ Nigh, LR Carley, W Maly - Computer Design: VLSI in Computers and Processors, 1988. ..., 1988 - [ieeexplore.ieee.org](#)

... a forward-biased diode, and appears only during transient current peaks as ... and CF
Hawkins, "h.leasurements of Quiescent Power Supply Current for ChfOS ...

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Experimental analysis of transient current testing based on chargeobservation

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... current and changed only the transient part of ... Open circuits caus- ing quiescent current elevation in latch ... with this technique; it drew less current than the ...

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Defect-oriented test methodology for complex mixed-signal circuits

FCM Kuijstermans, M Sachdev, AP Thijssen - European Design and Test Conference, 1995. ED&TC 1995, ..., 1995 - [ieeexplore.ieee.org](#)

... In a Class AB amplifier can be detected by simple DC, Transient and AC ... in the analog domain, the output of a fault-free circuit ... Its quiescent current is zero ...

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Comparison of defect detection capabilities of current-based andvoltage-based test methods

- [►lirmm.fr \(pdf\)](#)

B Kruseman - European Test Workshop, 2000. Proceedings. IEEE, 2000 - [ieeexplore.ieee.org](#)

... over a decade ago when quiescent current test- ing ... Dynamic current-based tests or transient current testing (IDDT ... For example delay fault testing requires more ...

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Current-Based Testing for Deep-Submicron VLSIs - ►uwaterloo.ca (pdf)

M Sachdev - IEEE DESIGN & TEST OF COMPUTERS, 2001 - [doi.ieeeecs.org](#)

... VLSI with very high (>100 mA) quiescent current, the application ... to identify a smooth, monotonic transient-current waveform ... of a deep-micron current-based test ...

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I DDQ testing and defect classes-a tutorial

JM Soden, CF Hawkins - Custom Integrated Circuits Conference, 1995., Proceedings of ..., 1995 - ieeexplore.ieee.org

... Physical shorts and their related fault models bring to mind an ... ma; seem costly to reject ICs that have increased quiescent power supply current but are ...

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J Plusquellic, D Chiarulli, S Levitan - INTERNATIONAL TEST CONFERENCE, 1997 - doi.ieeecs.org

... all nodes have stabilized to a quiescent value [12 ... Several dynamic supply current (I DD -based) approaches ... frequency components of the transient signals combine ...

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M Hashizume, M Ichimiya, H Yotsuyanagi, T Tamesada - Proc. Design, Automation and Test in Europe, 2001 - doi.ieeeecomputersociety.org

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Experimental Results on BIC Sensors for Transient Current Testing

R Picos, M Roca, E Isern, J Segura, E García- ... - Journal of Electronic Testing, 2000 - Springer

... the activation of the faults by enabling or ... In sensor based on transient current integration (charge) show ... defects raising the quiescent current consumption (I ...

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Built-in current sensor for/spl Delta/I/sub DDQ/testing - upc.es (PDF)

JR Vazquez, J Pineda de Gyvez - Solid-State Circuits, IEEE Journal of, 2004 - ieeexplore.ieee.org

... 2 by the current source and the capacitance) is in the quiescent state, then ... operating mode, the switch is closed and in each transient, a voltage ...

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